

Notice of References Cited	Application/Control No. 10/665,772		Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner JEONG S. PARK		Art Unit 2454	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,330,621	12-2001	Bakke et al.	710/5
*	C	US-6,128,644	10-2000	Nozaki, Hideki	709/203
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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